

General Description

30N60P the silicon N-channel Enhanced VDMOSFET, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency, which accords with the RoHS standard.

Product Summary			
V _{DS}	R _{DS(on)} (Ω) Typ	I _D (A)	Q _g (Typ)
600V	0.21 @ 10V	30	64nc

Features

- Fast switching
- Low Gate Charge
- Low on resistance
- Excellent avalanche characteristics

TO-247



Mechanical Data

- Case: TO-247 Package

Application

- Power switch circuit of adaptor and charger.

Block Diagram

Pin Definition:

1. Gate
2. Drain
3. Source

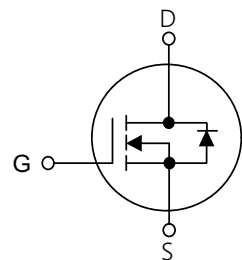


Table1 Absolute Maximum Ratings (T_c=25°C, unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V _{DS}	600	V
Gate-Source Voltage	V _{GS}	±30	V
Continuous Drain Current	I _D	T _c =25°C	30
		T _c =100°C	15.7
Pulsed Drain Current (Note 1)	I _{DM}	100	A
Single Pulse Avalanche Energy (Note 2)	E _{AS}	1500	mJ
Power Dissipation T _c =25°C	P _D	300	W
Operating Junction and Storage Temperature	T _J /T _{STG}	-55 ~ +150	°C

Table 2. Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance Junction to Ambient	$R_{\theta JA}$	62.5	$^{\circ}C/W$
Thermal resistance Junction to Case	$R_{\theta JC}$	0.42	$^{\circ}C/W$

Table 3. Electrical Characteristics ($T_J=25^{\circ}C$, unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	600			V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=600V, V_{GS}=0V$			1	μA
Gate- Source Leakage Current	Forward	I_{GSS}			100	nA
	Reverse				-100	nA
On Characteristics(Note 4)						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250mA$	2		4	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=15A$		0.21	0.27	Ω
Dynamic Characteristics(Note 5)						
Input Capacitance	C_{ISS}	$V_{DS}=25V, V_{GS}=0V, f=1MHz$		3487		pF
Output Capacitance	C_{OSS}			214		pF
Reverse Transfer Capacitance	C_{RSS}			10		pF
Switching Characteristics (Note 5)						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=250V, I_D=30A,$ $V_{GS}=10V, R_G=10\Omega$		37.2		ns
Turn-On Rise Time	t_r			64.4		ns
Turn-Off Delay Time	$t_{d(off)}$			86.8		ns
Turn-Off Fall Time	t_f			46		ns
Total Gate Charge	Q_G	$V_{DD}=400V, I_D=30A,$ $V_{GS}=10V$		64		nC
Gate-Source Charge	Q_{GS}			17		nC
Gate-Drain Charge	Q_{GD}			23		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S=30A$			1.5	V
Maximum Continuous Drain-Source Diode Forward Current	I_S			30		A
Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_S=30A$		490		ns
Reverse Recovery Charge	Q_{RR}	$di/dt=100A/\mu s$ (Note 1)		6246		nC

Notes : 1 Repetitive Rating: Pulse width limited by maximum junction temperature

2 $L=10mH, I_D=17.3A$, Starting $T_J=25^{\circ}C$

3 $I_{SD}=30A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DSS}$, starting $T_J=25^{\circ}C$

4 Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

5 Guaranteed by design, not subject to production

Typical Characteristics Diagrams

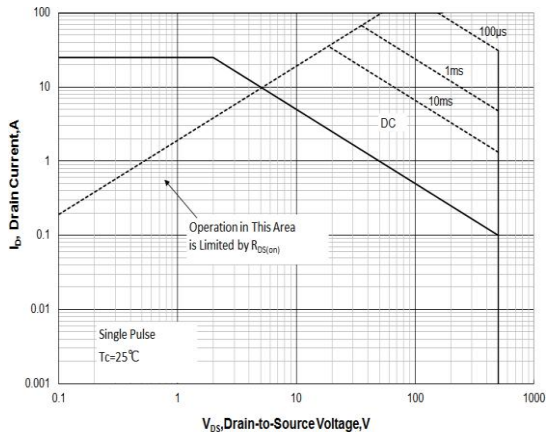


Figure 1 Maximum Forward Bias Safe Operating Area

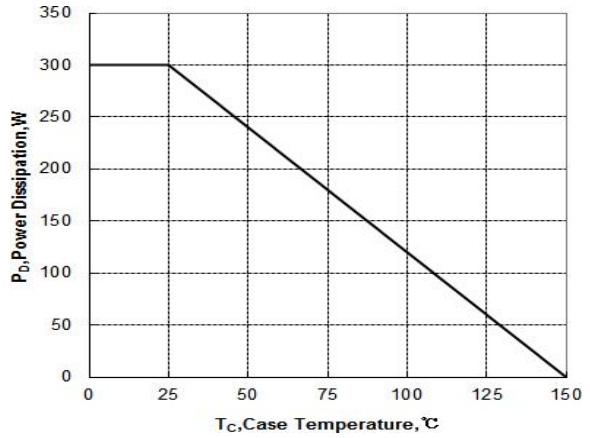


Figure 2 Maximum Power dissipation vs Case Temperature

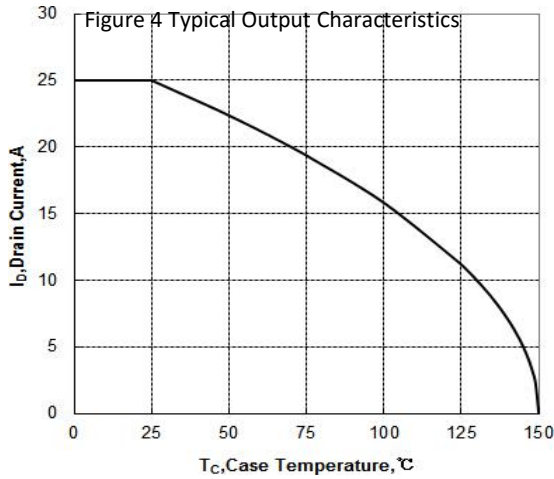


Figure 3 Maximum Continuous Drain Current vs Case Temperature

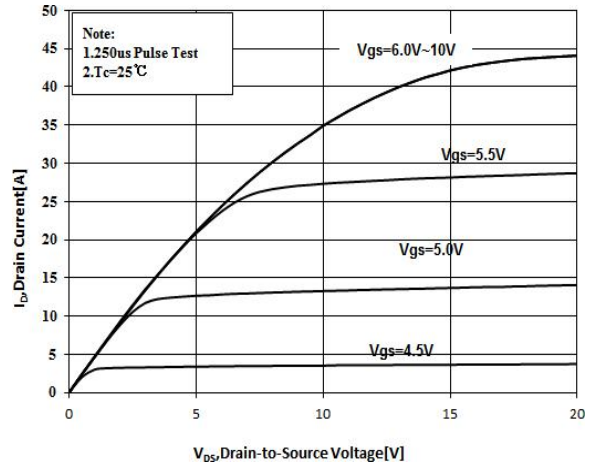


Figure 4 Typical Output Characteristics

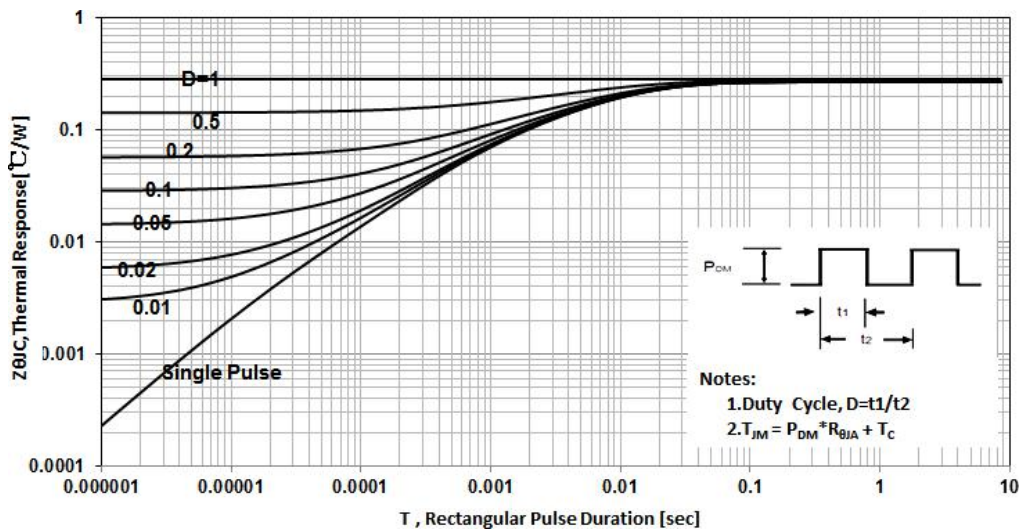


Figure 5 Maximum Effective Thermal Impedance , Junction to Case

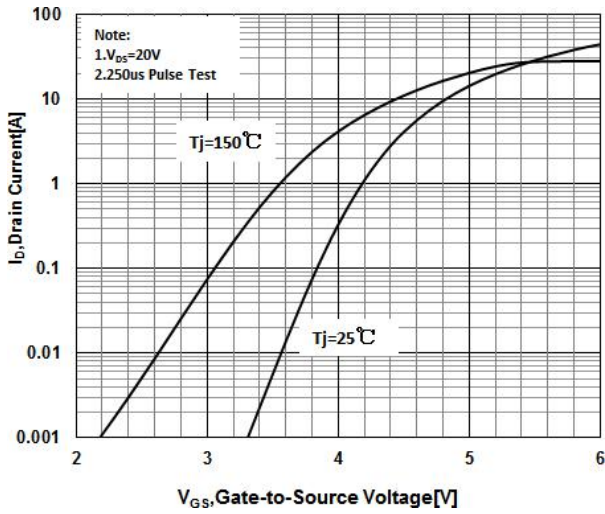


Figure 6 Typical Transfer Characteristics

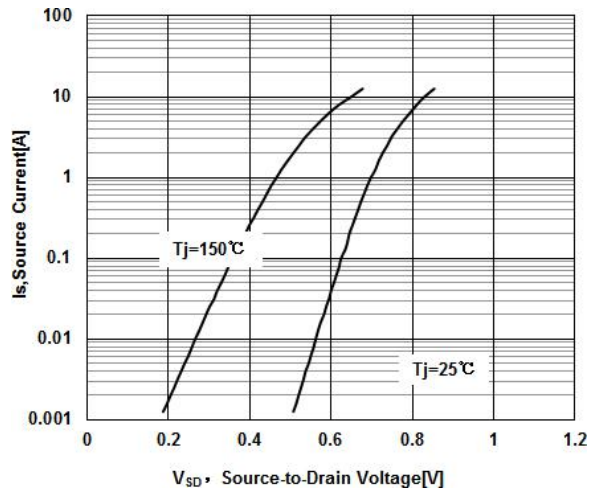


Figure 7 Typical Body Diode Transfer Characteristics

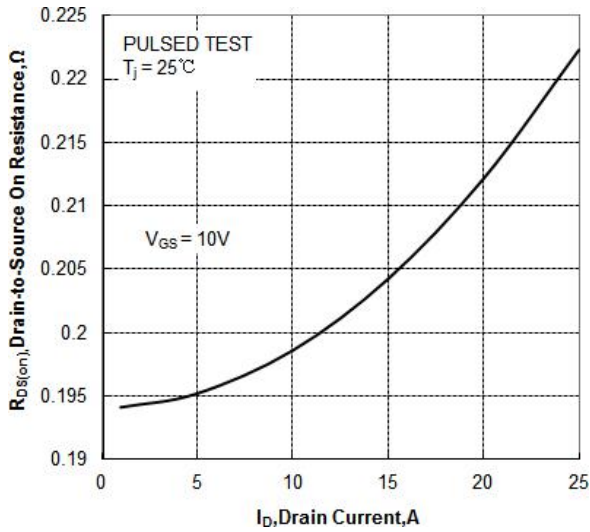


Figure 8 Typical Drain to Source ON Resistance vs Drain Current

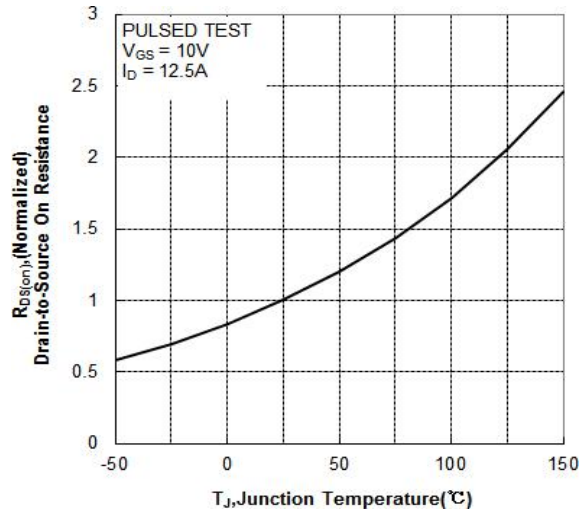


Figure 9 Typical Drain to Source on Resistance vs Junction Temperature

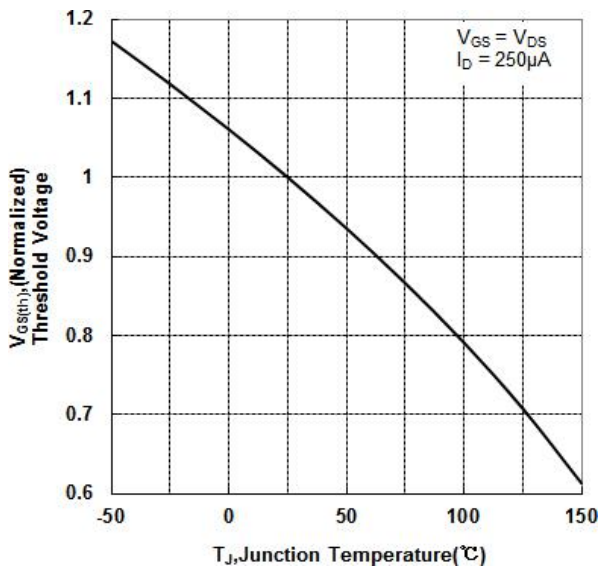


Figure 10 Typical Threshold Voltage vs Junction Temperature

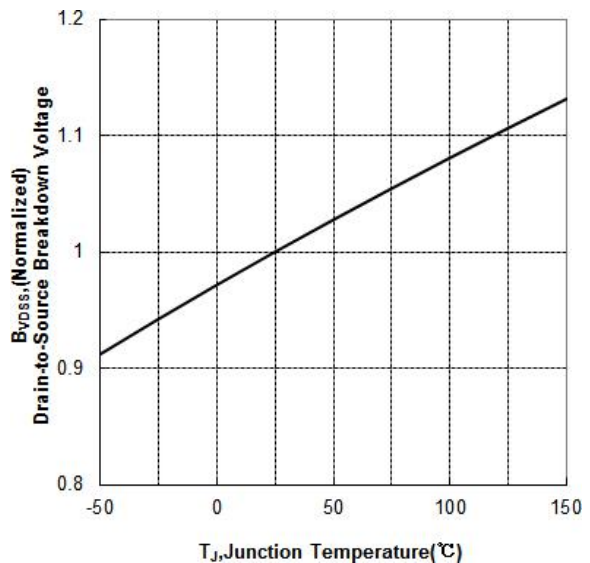


Figure 11 Typical Breakdown Voltage vs Junction Temperature

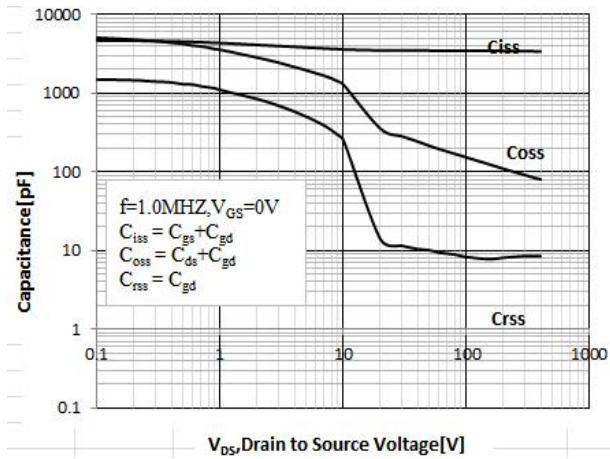


Figure 12 Typical Capacitance vs Drain to Source Voltage

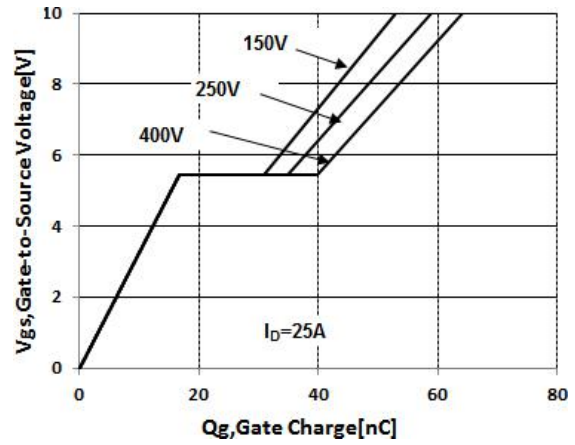


Figure 13 Typical Gate Charge vs Gate to Source Voltage

Typical Test Circuit

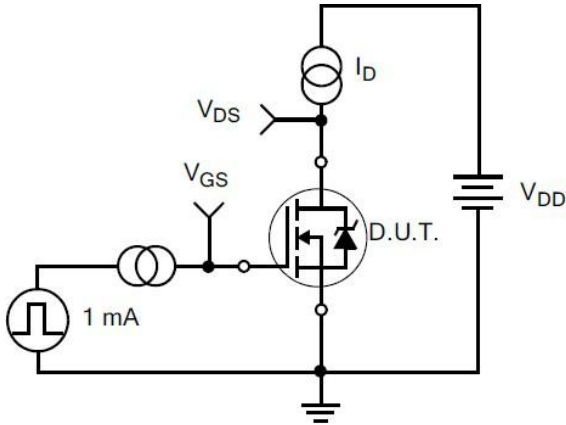


Figure 17. Gate Charge Test Circuit

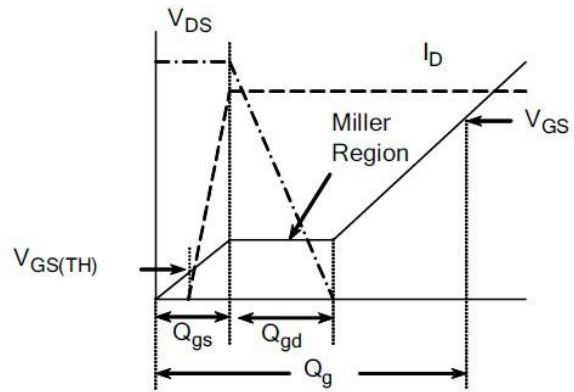


Figure 18. Gate Charge Waveform

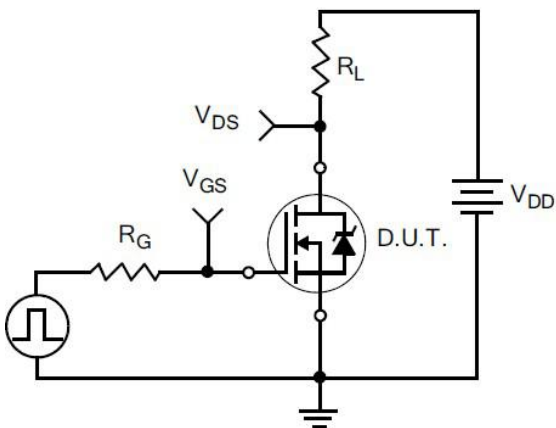


Figure 19. Resistive Switching Test Circuit

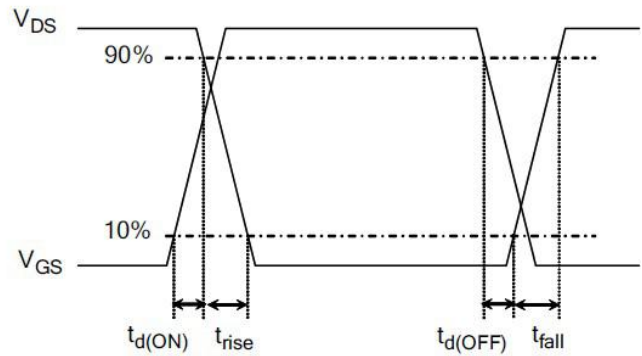


Figure 20. Resistive Switching Waveforms

Typical Test Circuit

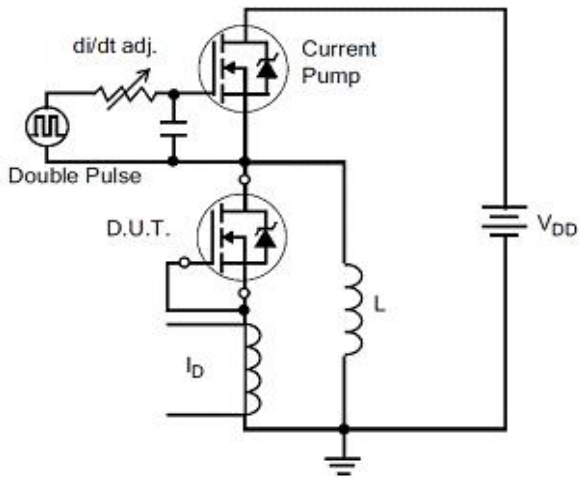


Figure 21. Diode Reverse Recovery Test Circuit

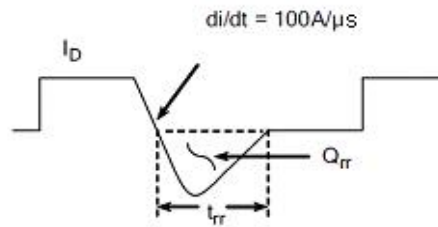


Figure 22. Diode Reverse Recovery Waveform

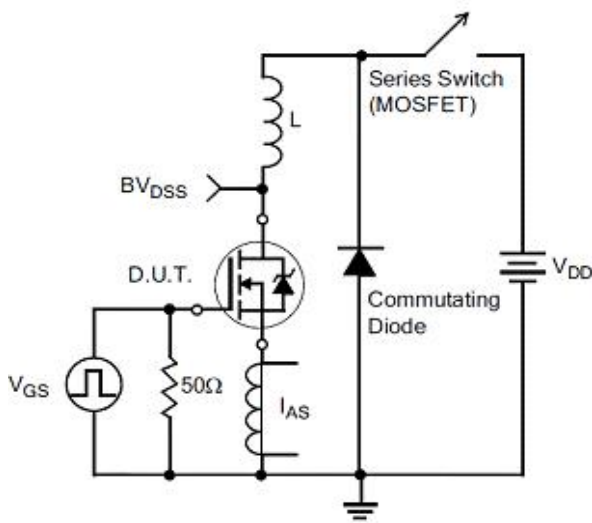


Figure 23. Unclamped Inductive Switching Test Circuit

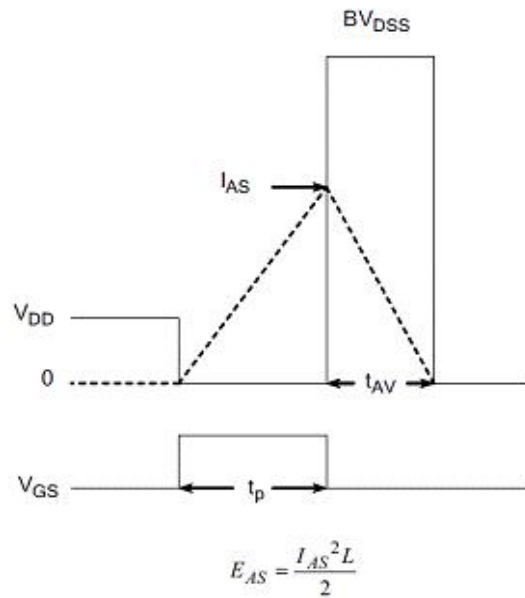
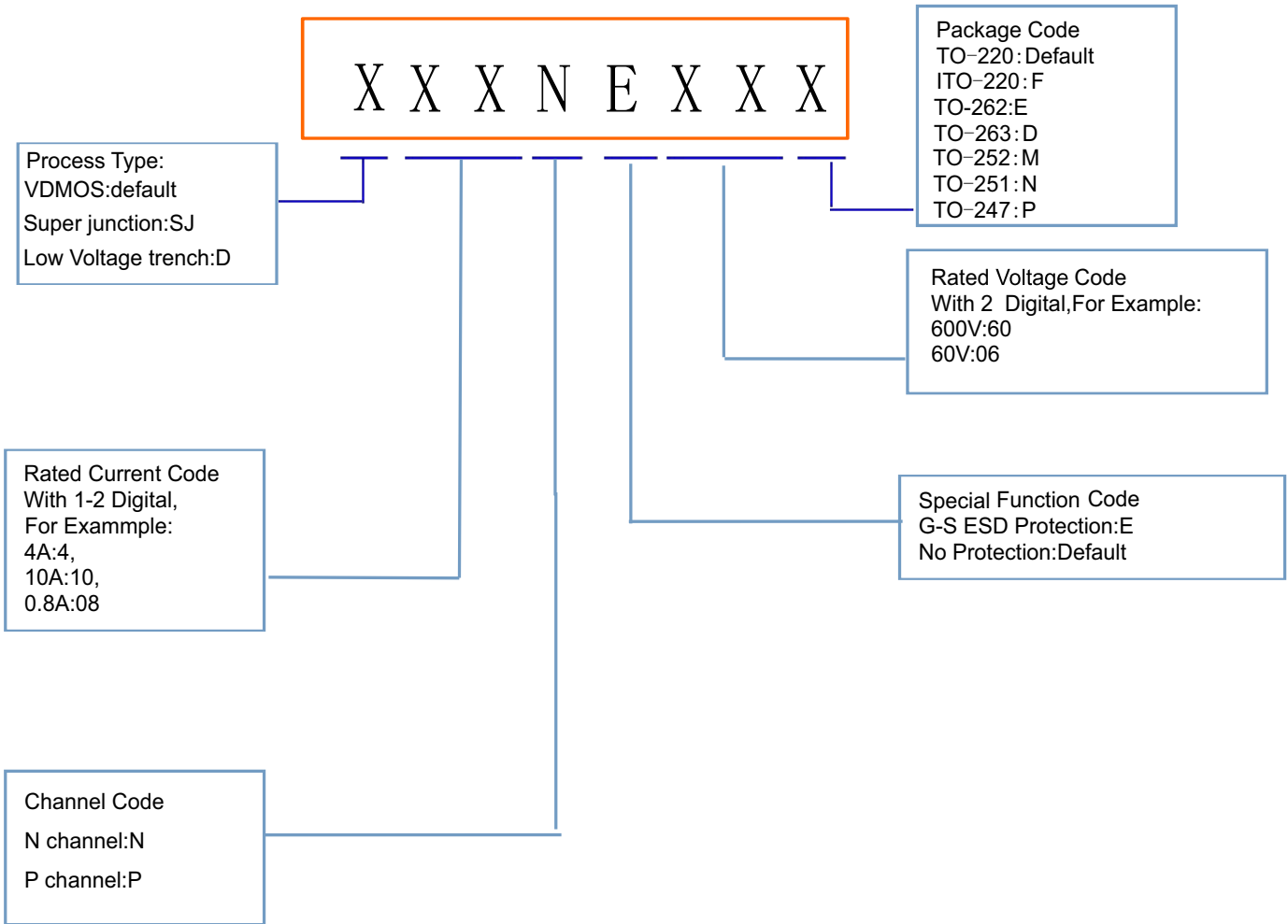


Figure 24. Unclamped Inductive Switching Waveforms

Product Names Rules



Friendship Reminder

■ JiNan JingHeng (hereinafter referred to as JH) reserves the right to make changes to this document and its products and specifications at anytime without notice.

济南晶恒（以下简称 JH）保留未经通知，变更本文件和与本文件相关的产品及规格的权利。

■ Customers should obtain and confirm the latest product information and specifications before final design, purchase or use.

使用方应在使用、采购本产品之前获取并确认产品信息和规格书的最新版本。

■ JH makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does JH assume any liability for application assistance or customer product design.

JH 对其产品用于某特定用途的适用性，既不做任何保证、说明或担保，也不承担任何应用协助或使用方设计的法定责任。

■ JH does not warrant or accept any liability with products which are purchased or used for any unintended or unauthorized application.

JH 不保证或承担任何责任，其产品被采购使用于任何非预期或授权的应用，

■ No license is granted by implication or otherwise under any intellectual property rights of JH.

此规格书属于 JH 的知识产权,没有经过我司授权不得抄袭。

■ JH's products are not authorized for use as critical components in life support devices or systems without express written approval of JH.

没有 JH 的书面授权，JH 的产品不能在生命支撑设备或系统里作为关键零件使用。